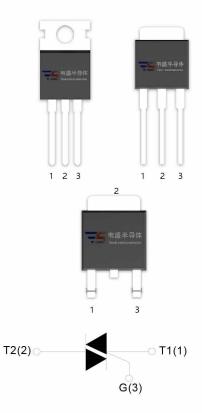


DESCRIPTION:

BT138-SS triacs with low holding and latching current are especially recommended for use on middle and small resistance type power load.



MAIN FEATURES

Symbol	Value	Unit
I _{T(RMS)}	12	Α
V _{DRM} /V _{RRM}	600/800	V

ABSOLUTE MAXIMUM RATINGS

Parameter		Symbol	Value	Unit
Storage junction temperature range		T _{stg}	-40-150	$^{\circ}$
Operating junction temperature range		Tj	-40-125	$^{\circ}$
Repetitive peak off-state voltage(Tj=25℃)		V _{DRM}	600/800	V
Repetitive peak reverse voltage(Tj=25℃)		V _{RRM}	600/800	V
Non repetitive surge peak Off-state voltage		V _{DSM}	V _{DRM} + 100	V
Non repetitive peak reverse voltage		V _{RSM}	V _{RRM} + 100	V
RMS on-state current	TO-251/ TO-220C(T _C =95°C) TO-220F(Ins) (T _C =80°C)	- I _{T(RMS)}	12	А
Non repetitive surge peak on-state current (full cycle, F=50Hz)		Ітѕм	95	Α
I ² t value for fusing (tp=10ms)		l ² t	45	A ² s



Critical rate of rise of on-state	I - II -III	dl/dt	50	Λ/μο	
current(I _G =2×I _{GT})	IV		10	√ A/μs	
Peak gate current		I _{GM}	2	Α	
Average gate power dissipation		P _{G(AV)}	0.5	W	
Peak gate power		P _{GM}	5	W	

ELECTRICAL CHARACTERISTICS (T_j=25°C unless otherwise specified)

Symbol	Test Condition (Quadrant		Value		Unit	
	rest Condition			D	E	F	Unit
laz	V _D =12V R _L =33Ω	I - II -III	MAX	5	10	25	mA
I _{GT}		IV		10	25	70	
V _{GT}		ALL	MAX		1.5		V
V _{GD}	$V_D=V_{DRM}$ $T_j=125$ °C $R_L=3.3$ $KΩ$	ALL	MIN	0.2		V	
IL	I _G =1.2I _{GT}	I - III	MAX	15	30	40	mA
		II - IV		20	40	80	
lн	I _T =100mA		MAX	10	25	30	mA
dV/dt	V _D =2/3V _{DRM} Gate Open T _j =125℃		MIN	20	50	50	V/µs

STATIC CHARACTERISTICS

Symbol	Parameter		Value(MAX)	Unit
V _{TM}	I _{тм} =15A tp=380µs	Tj=25℃	1.6	V
I _{DRM}	VD=VDRM VR=VRRM	Tj=25℃	5	μΑ
I _{RRM}		Tj=125℃	1	mA

THERMAL RESISTANCES

Symbol	Parameter		Value	Unit
R _{th(j-c)}	junction to case(AC)	TO-220C	1.4	°C/W
		TO-220F(Ins)	2.5	
		TO-251	1.7	

Vseei Semiconductor Co., Ltd



FIG.1: Maximum power dissipation versus RMS on-state current

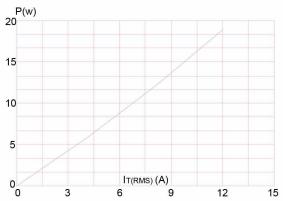


FIG.3: Surge peak on-state current versus number of cycles

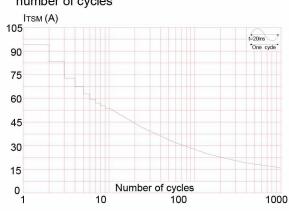


FIG.2: RMS on-state current versus case temperature

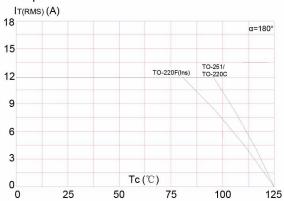


FIG.4: On-state characteristics (maximum values)

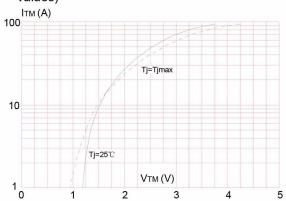




FIG.5: Non-repetitive surge peak on-state current for a sinusoidal pulse with width tp<20ms, and corresponging value of $I^2t(I-II-III:dI/dt<50A/\mu s;IV:dI/dt<10A/\mu s)$

ITSM (A), $I^2 t (A^2 s)$

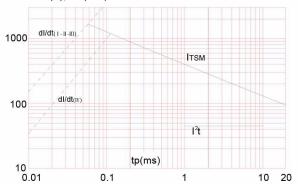


FIG.7: Relative variations of holding current versus junction temperature

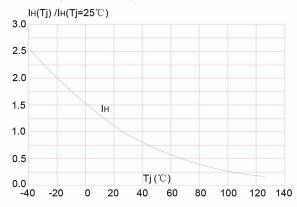


FIG.6: Relative variations of gate trigger current versus junction temperature

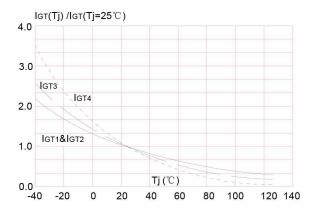


FIG.8: Relative variations of latching current versus junction temperature

